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捷多邦, 专业PCB打样**\$N54AL\$29**8世**\$**N74AL\$299 8-BIT UNIVERSAL SHIFT/STORAGE REGISTERS WITH 3-STATE OUTPUTS

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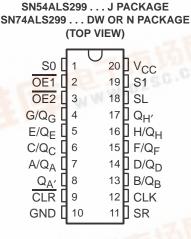
- Multiplexed I/O Ports Provide Improved Bit
 Density
- Four Modes of Operation:
 - Hold (Store)
 - Shift Right
 - Shift Left
 - Load Data
- Operate With Outputs Enabled or at High Impedance
- 3-State Outputs Drive Bus Lines Directly
- Can Be Cascaded for n-Bit Word Lengths
- Direct Overriding Clear
- Applications:
 - Stacked or Push-Down Registers
 - Buffer Storage
 - Accumulator Registers
- Package Options Include Plastic Small-Outline (DW) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

description

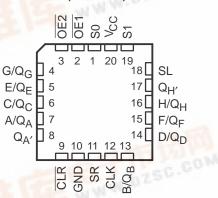
These 8-bit universal shift/storage registers feature multiplexed I/O ports to achieve full 8-bit data handling in a single 20-pin package. Two function-select (S0, S1) inputs and two outputenable (OE1, OE2) inputs can be used to choose the modes of operation listed in the function table.

Synchronous parallel loading is accomplished by taking both S0 and S1 high. This places the 3-state outputs in the high-impedance state and permits data applied on the I/O ports to be clocked into the register. Reading out of the register can be accomplished while the outputs are enabled in any mode. Clearing occurs asynchronously when the clear (CLR) input is low. Taking either OE1 or OE2 high disables the outputs, but has no effect on clearing, shifting, or storing data.

The SN54ALS299 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74ALS299 is characterized for operation from 0°C to 70°C.









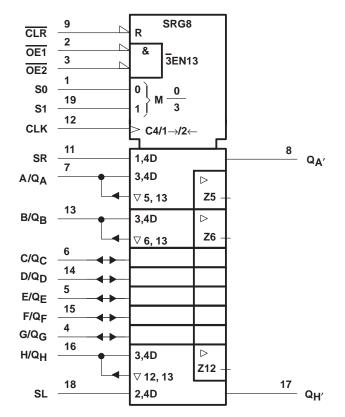
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	FUNCTION TABLE																	
MODE		INPUTS					I/O PORTS						OUTPUTS					
MODE	CLR	S 1	S0	OE1†	OE2†	CLK	SL	SR	A/Q _A	B/Q _B	C/Q _C	D/QD	E/Q _E	F/Q _F	G/Q _G	H/Q _H	$Q_{A'}$	$Q_{H'}$
Clear	L L L	X L H	L X H	L L X	L L X	X X X	X X X	X X X	L L X	L L L	L L L							
Hold	H H	L X	L X	L L	L L	X L	X X	X X	Q _{A0} Q _{A0}	Q _{B0} Q _{B0}	Q _{C0} Q _{C0}	Q _{D0} Q _{D0}	Q _{E0} Q _{E0}	Q _{F0} Q _{F0}	Q _{G0} Q _{G0}	Q _{H0} Q _{H0}	Q _{A0} Q _{A0}	Q _{H0} Q _{H0}
Shift Right	H H	L L	H H	L L	L L	$\stackrel{\uparrow}{\uparrow}$	X X	H L	H L	Q _{An} Q _{An}	Q _{Bn} Q _{Bn}	Q _{Cn} Q _{Cn}	Q _{Dn} Q _{Dn}	Q _{En} Q _{En}	Q _{Fn} Q _{Fn}	Q _{Gn} Q _{Gn}	H L	Q _{Gn} Q _{Gn}
Shift Left	нн	H H	L	L	L	↑ ↑	H L	X X	Q _{Bn} Q _{Bn}	Q _{Cn} Q _{Cn}	Q _{Dn} Q _{Dn}	Q _{En} Q _{En}	Q _{Fn} Q _{Fn}	Q _{Gn} Q _{Gn}	Q _{Hn} Q _{Hn}	H L	Q _{Bn} Q _{Bn}	H L
Load	Н	Н	Н	Х	Х	\uparrow	Х	Х	а	b	С	d	е	f	g	h	а	h

NOTE: a . . . h = the level of the steady-state inputs A through H, respectively. This data is loaded into the flip-flops while the flip-flop outputs are isolated from the I/O terminals.

[†] When one or both output-enable inputs are high, the eight I/O terminals are disabled to the high-impedance state; however, sequential operation or clearing of the register is not affected.

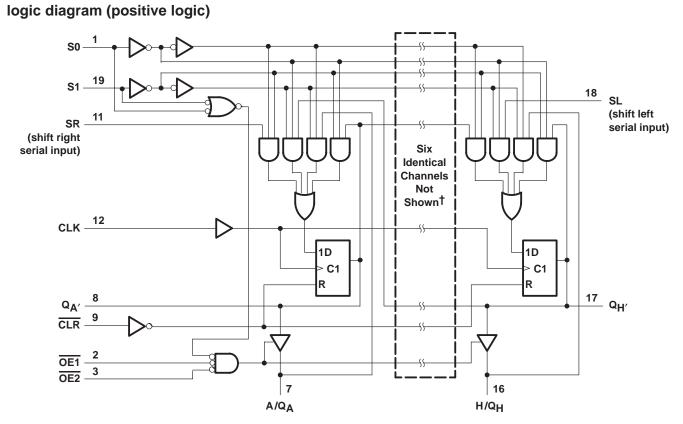
logic symbol[‡]



[‡] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



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 \dagger I/O ports not shown: B/Q_B (13), C/Q_C (6), D/Q_D (14), E/Q_E (5), F/Q_F (15), and G/Q_G (4).

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[‡]

Supply voltage, V _{CC} Input voltage, V _I : All inputs	
I/O ports	
Operating free-air temperature range, T _A : SN54ALS299	. −55°C to 125°C
SN74ALS299	0°C to 70°C
Storage temperature range	. −65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.



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recommended operating conditions

			SN	54ALS2	99	SN74ALS299			UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage		4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage		2			2			V
VIL	Low-level input voltage				0.7			0.8	V
1	Ligh lovel output ourrest	Q _{A'} or Q _{H'}			-0.4			-0.4	mA
ЮН	High-level output current	$Q_A - Q_H$			-1			-2.6	ШA
1		Q _{A'} or Q _{H'}			4			8	A
IOL	Low-level output current	$Q_A - Q_H$			12			24	mA
ТА	Operating free-air temperature		-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

		TEST OF	NDITIONS	SN	54ALS2	99	SN			
F	PARAMETER	TEST CO	ONDITIONS	MIN	TYP [†]	MAX	MIN	TYP [†]	MAX	UNIT
VIK		V _{CC} = 4.5 V,	lj = - 18 mA			-1.5			-1.5	V
	All outputs	$V_{CC} = 4.5 V \text{ to } 5.5 V,$	I _{OH} = - 0.4 mA	V _{CC} -2	2		V _{CC} -2	2		
VOH		V _{CC} = 4.5 V	I _{OH} = – 1 mA	2.4	3.3					V
	Q _A – Q _H	VCC = 4.5 V	I _{OH} = - 2.6 mA				2.4	3.2		
	Q _A ' or Q _H '	V _{CC} = 4.5 V	$I_{OL} = 4 \text{ mA}$		$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	0.25	0.4			
Ver		VCC = 4.5 V	I _{OL} = 8 mA					0.35	0.5	V
VOL		V _{CC} = 4.5 V	I _{OL} = 12 mA		0.25	0.4		0.25	0.4	v
	Q _A – Q _H	VCC = 4.3 V	I _{OL} = 24 mA					0.35	0.5	
η	A – H		VI = 5.5 V			0.1			0.1	mA
Ч	Any others	V _{CC} = 5.5 V	V _I = 7 V			0.1			0.1	MA
IIH‡		V _{CC} = 5.5 V,	VI = 2.7 V			20			20	μA
. +	S0, S1, SR, SL					-0.2			-0.2	mA
IIL‡	Any others	V _{CC} = 5.5 V,	$V_{I} = 0.4 V$			-0.1			-0.1	ША
. 6	$Q_{A'}$ or $Q_{H'}$		1/2 - 2.25	-15		-70	-15		-70	mA
IO§	Q _A -Q _H	V _{CC} = 5.5 V,	V _O = 2.25 V	-20		-112	-30		-112	mA
			Outputs high		15	28		15	28	
ICC		V _{CC} = 5.5 V	Outputs low		22	38		22	38	mA
			Outputs disabled		23	40		23	40	

[†] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

 \ddagger For I/O ports (Q_A-Q_H), the parameters I_{IH} and I_{IL} include the off-state output current.

§ The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.



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timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

				SN54A	LS299	SN74A	UNIT	
				MIN	MAX	MIN	MAX	UNIT
fclock	Clock frequency (at 50% duty cycle)			0	17	0	30	MHz
tw	Pulse duration	CLK high or low				16.5		
١W	Fuise duration	CLR low	12		10		ns	
		S0 or S1	25		20			
	Setup time before CLK [↑]		High	18		16		
t _{su}		Serial or parallel data		15		6		ns
	Inactive-state setup time before CLK ^{↑†}	CLR				15		
		S0 or S1	0		0			
th	Hold time after CLK↑	Serial or parallel data	0		0		ns	

[†] Inactive-state setup time is also referred to as recovery time.

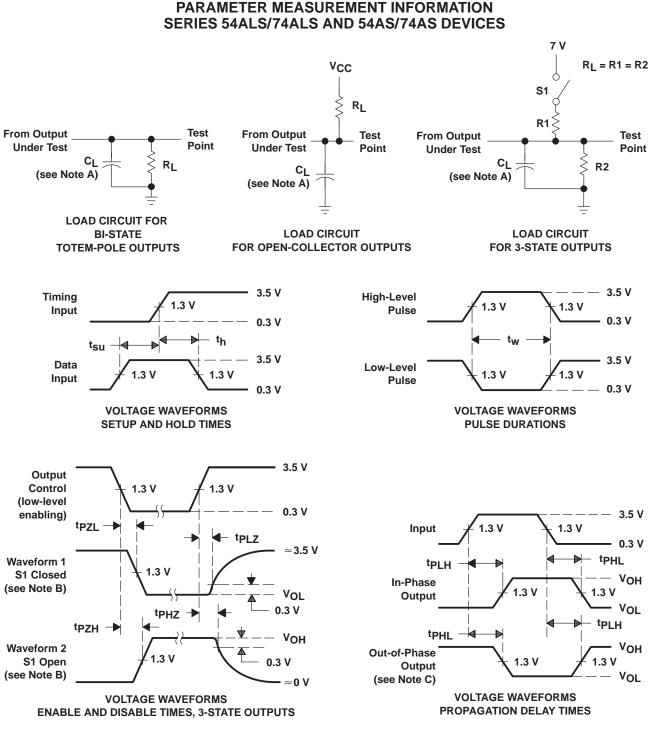
switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	ТО (О U ТРUТ)	CL R1 R2	V _{CC} = 4.5 V to 5.5 V, C _L = 50 pF, R1 = 500 Ω, R2 = 500 Ω, T _A = MIN to MAX [‡]					
			SN54A	LS299	SN74A				
			MIN	MAX	MIN	MAX			
fmax			17		30		MHz		
^t PLH	CLK		2	19	4	13	ns		
^t PHL	CLK	Q _A –Q _H	4	25	7	19	115		
^t PLH	CLK	$Q_{A^{\prime}}$ or $Q_{H^{\prime}}$	2	21	5	15	ns		
^t PHL	CLK		4	25	8	18	113		
4- 1.11		Q _A -Q _H	6	29	6	22			
^t PHL	CLR	Q _{A′} or Q _{H′}	6	29	6	22	ns		
^t PZH		<u> </u>	5	22	6	16			
^t PZL	OE1, OE2	$Q_A - Q_H$	6	27	8	22	ns		
^t PZH	00.04	0 0	5	27	7	17			
^t PZL	S0, S1	$Q_A - Q_H$	6	26	8	22	ns		
^t PHZ		0.0	1	15	1	8			
^t PLZ	OE1, OE2	$Q_A - Q_H$	4	38	5	15	ns		
^t PHZ	S0, S1	0.00	1	16	1	12			
^t PLZ	30, 31	$Q_A - Q_H$	4	34	8	25	ns		

[‡] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



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NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
- D. All input pulses have the following characteristics: PRR \leq 1 MHz, t_r = t_f = 2 ns, duty cycle = 50%.
- E. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms



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